Memory FRAM

64K (8K \times 8) Bit SPI

MB85RS64VY(AEC-Q100 Compliant)

■ DESCRIPTION

MB85RS64VY is a FRAM (Ferroelectric Random Access Memory) chip in a configuration of 8,192 words \times 8 bits, using the ferroelectric process and silicon gate CMOS process technologies for forming the nonvolatile memory cells. This product is specifically targeted for high-temperature environment such as automotive applications.

MB85RS64VY adopts the Serial Peripheral Interface (SPI).

The MB85RS64VY is able to retain data without using a back-up battery, as is needed for SRAM. The memory cells used in the MB85RS64VY can be used for 10¹³ read/write operations, which is a significant improvement over the number of read and write operations supported by Flash memory and E²PROM. As MB85RS64VY does not need any waiting time in writing process, the write cycle time of MB85RS64VY is much shorter than that of Flash memories or E²PROM.

■ FEATURES

• Bit configuration : 8,192 words × 8 bits

• Serial Peripheral Interface : SPI (Serial Peripheral Interface)

Correspondent to SPI mode 0 (0, 0) and mode 3 (1, 1)

• Operating frequency : 25 MHz (Max,@2.7V to 4.5V), 33MHz(Max,@4.5V to 5.5V)

 $\begin{array}{ll} \bullet \ \ \mbox{High endurance} & : 10^{13} \ \mbox{times / byte} \\ \bullet \ \mbox{Data retention} & : 40.2 \ \mbox{years (+85 °C)}, \end{array}$

10.9 years (+105 °C)

3.3 years (+125 °C) or more

Under evaluation for more than 3.3 years(+125 °C)

Operating power supply voltage : 2.7V to 5.5V

Low power consumption : Operating power supply current

1.8 mA (Max@25 MHz),2.3 mA (Max@33MHz)

Standby current 30 μA (Max) Sleep current 12 μA (Max)

Operation ambient temperature range : – 40 °C to +125 °C

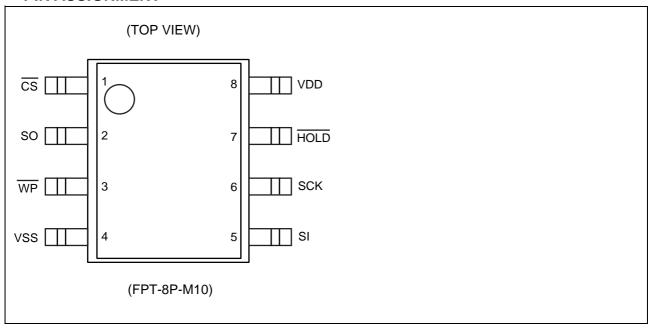
Package : 8-pin plastic SOP (FPT-8P-M10)

AEC-Q100 Grade 1 compliant

RoHS compliant



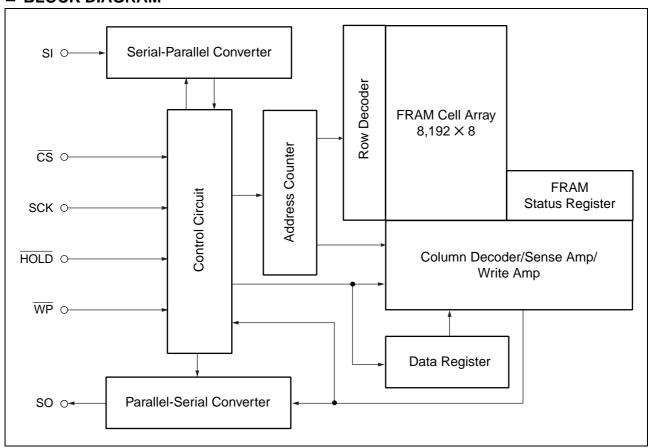
■ PIN ASSIGNMENT



■ PIN FUNCTIONAL DESCRIPTIONS

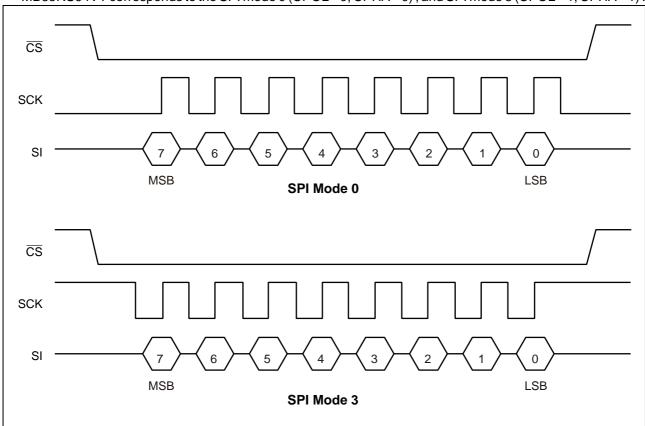
Pin No.	Pin Name	Functional description
1	CS	Chip Select pin This is an input pin to make chips select. When \overline{CS} is "H" level, device is in deselect (standby) status and SO becomes High-Z. Inputs from other pins are ignored for this time. When \overline{CS} is "L" level, device is in select (active) status. \overline{CS} has to be "L" level before inputting op-code.
3	WP	Write Protect pin This is a pin to control writing to a status register. The writing of status register (see "■ STATUS REGISTER") is protected in related with WP and WPEN. See "■ WRITING PROTECT" for detail.
7	HOLD	Hold pin This pin is used to interrupt serial input/output without making chips deselect. When HOLD is "L" level, hold operation is activated, SO becomes High-Z, SCK and SI become do not care. See "■ HOLD OPERATION" for detail.
6	SCK	Serial Clock pin This is a clock input pin to input/output serial data. SI is loaded synchronously to a rising edge, SO is output synchronously to a falling edge.
5	SI	Serial Data Input pin This is an input pin of serial data. This inputs op-code, address, and writing data.
2	SO	Serial Data Output pin This is an output pin of serial data. Reading data of FRAM memory cell array and status register data are output. This is High-Z during standby.
8	VDD	Supply Voltage pin
4	VSS	Ground pin

■ BLOCK DIAGRAM



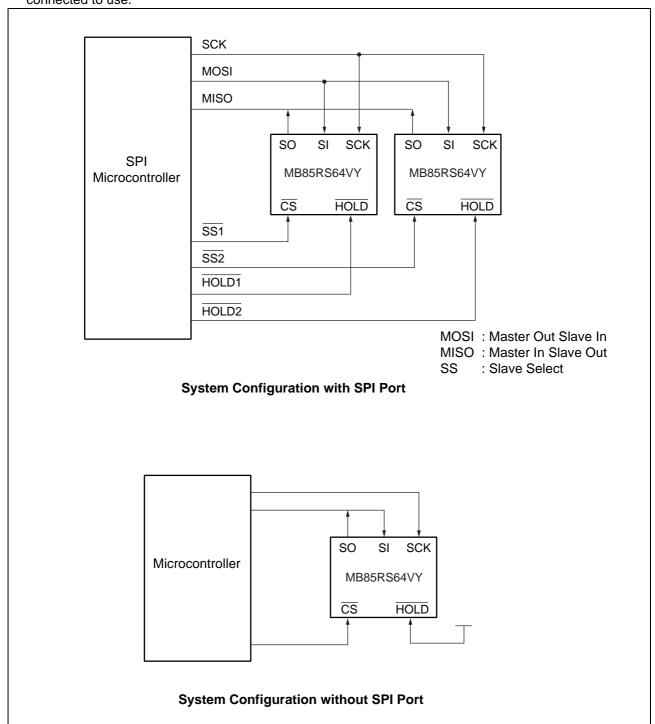
■ SPI MODE

MB85RS64VY corresponds to the SPI mode 0 (CPOL=0, CPHA=0), and SPI mode 3 (CPOL=1, CPHA=1).



■ SERIAL PERIPHERAL INTERFACE (SPI)

MB85RS64VY works as a slave of SPI. More than 2 devices can be connected by using microcontroller equipped with SPI port. By using a microcontroller not equipped with SPI port, SI and SO can be bus connected to use.



■ STATUS REGISTER

Bit No.	Bit Name	Function		
7	WPEN	Status Register Write Protect This is a bit composed of nonvolatile memories (FRAM). WPEN protects writing to a status register (refer to "■ WRITING PROTECT") relating with WP input. Writing with the WRSR command and reading with the RDSR command are possible.		
6 to 4	_	Not Used Bits These are bits composed of nonvolatile memories, writing with the WRSR command is possible. These bits are not used but they are read with the RDSR command.		
3	BP1	Block Protect This is a bit composed of nonvolatile memory. This defines size of write		
2	BP0	protect block for the WRITE command (refer to "■ BLOCK PROTECT"). Writing with the WRSR command and reading with the RDSR command are possible.		
1	WEL	Write Enable Latch This indicates FRAM Array and status register are writable. The WREN command is for setting, and the WRDI command is for resetting. With the RDSR command, reading is possible but writing is not possible with the WRSR command. WEL is reset after the following operations. After power ON. After WRDI command recognition. The following rising edges do not reset WEL. The rising edge of CS after WRSR command recognition. The rising edge of CS after WRITE command recognition.		
0	0	This is a bit fixed to "0".		

■ OP-CODE

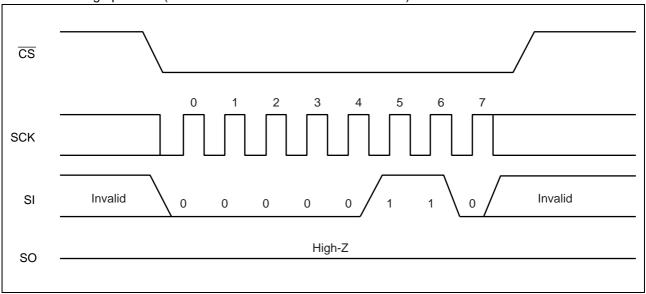
MB85RS64VY accepts 8 kinds of command specified in op-code. Op-code is a code composed of 8 bits shown in the table below. Do not input invalid codes other than those codes. If CS is risen while inputting op-code, the command are not performed.

Name	Description	Op-code
WREN	Set Write Enable Latch	0000 0110в
WRDI	Reset Write Enable Latch	0000 0100в
RDSR	Read Status Register	0000 0101в
WRSR	Write Status Register	0000 0001в
READ	Read Memory Code	0000 0011в
WRITE	Write Memory Code	0000 0010в
RDID	Read Device ID	1001 1111в
SLEEP	Sleep Mode	1011 1001в
		1100 0011в
RFU	Decembed for fixture use	1100 0110в
	Reserved for future use	1100 1110в
		1100 1111в

■ COMMAND

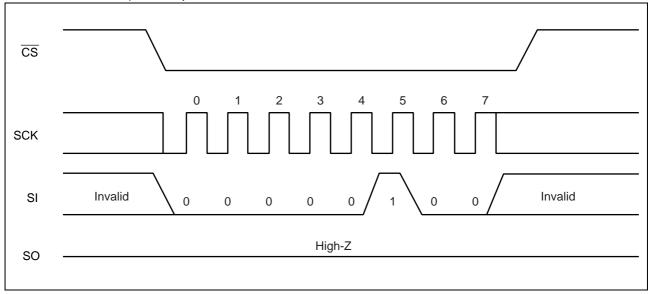
• WREN

The WREN command sets WEL (Write Enable Latch) bit to 1. WEL has to be set with the WREN command before writing operation (WRSR command and WRITE command).



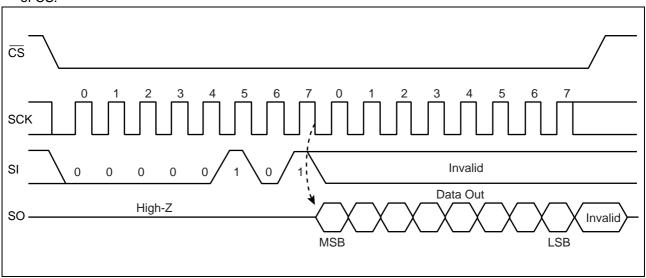
• WRDI

The WRDI command resets WEL (Write Enable Latch) bit to 0. Writing operation (WRSR command and WRITE command) are not performed when WEL is reset.



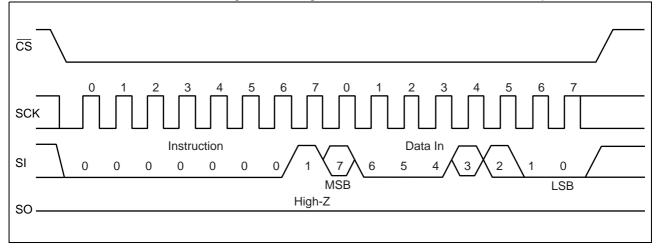
• RDSR

The RDSR command reads status register data. After op-code of RDSR is input to SI, 8-cycle clock is input to SCK. The SI value is invalid for this time. SO is output synchronously to a falling edge of SCK. In the RDSR command, repeated reading of status register is enabled by sending SCK continuously before rising of CS.



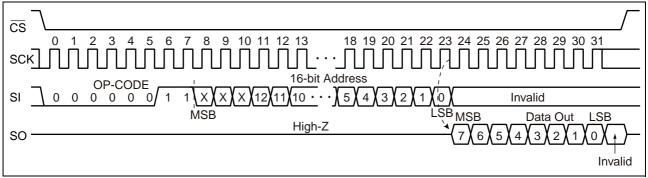
• WRSR

The WRSR command writes data to the nonvolatile memory bit of status register. After performing WRSR op-code to a SI pin, 8 bits writing data is input. WEL (Write Enable Latch) is not able to be written with WRSR command. A SI value correspondent to bit 1 is ignored. Bit <u>0 of</u> the status register is fixed to "0" and cannot be written. The SI value corresponding to <u>bit 0</u> is ignored. WP signal level shall be fixed before performing WRSR command, and do not change the <u>WP</u> signal level until the end of command sequence.



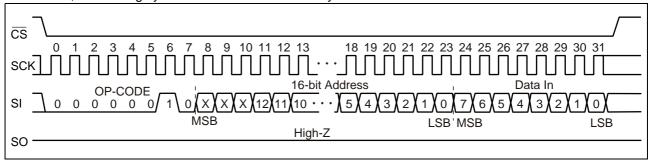
• READ

The READ command reads FRAM memory cell array data. Arbitrary 16 bits address and op-code of READ are input to SI. The upper three address bits are invalid. Then, 8-cycle clock is input to SCK. SO is output synchronously to the falling edge of SCK. While reading, the SI value is invalid. When $\overline{\text{CS}}$ is risen, the READ command is completed, but keeps on reading with automatic address increment which is enabled by continuously sending clocks to SCK in unit of 8 cycles before $\overline{\text{CS}}$ rising. When it reaches the most significant address, it rolls over to the starting address, and reading cycle keeps on infinitely.



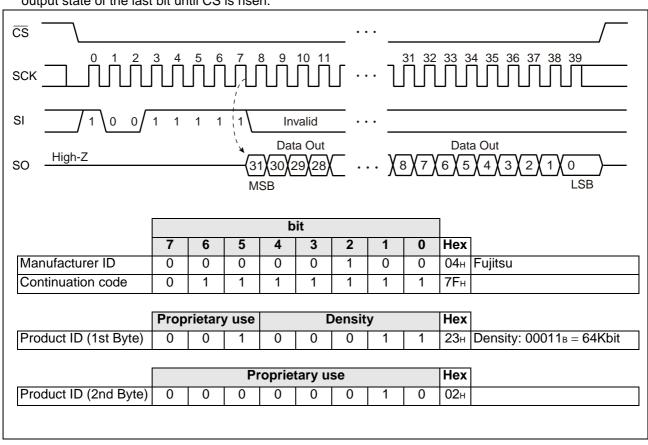
• WRITE

The WRITE command writes data to FRAM memory cell array. WRITE op-code, arbitrary 16 bits of address and 8 bits of writing data are input to SI. The upper three address bits are invalid. When 8 bits of writing data is input, data is written to FRAM memory cell array. Risen \overline{CS} will terminate the WRITE command, but if you continue sending the writing data for 8 bits each before \overline{CS} rising, it is possible to continue writing with automatic address increment. When it reaches the most significant address, it rolls over to the starting address, and writing cycle can be continued infinitely.



• RDID

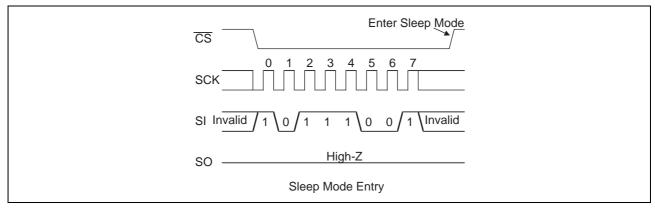
The RDID command reads fixed Device ID. After performing RDID op-code to SI, 32-cycle clock is input to SCK. The SI value is invalid for this time. SO is output synchronously to a falling edge of SCK. The output is in order of Manufacturer ID (8bit)/Continuation code (8bit)/Product ID (1st Byte)/Product ID (2nd Byte). In the RDID command, 32-bit Device ID is output by continuously sending SCK clock, and SO holds the output state of the last bit until CS is risen.



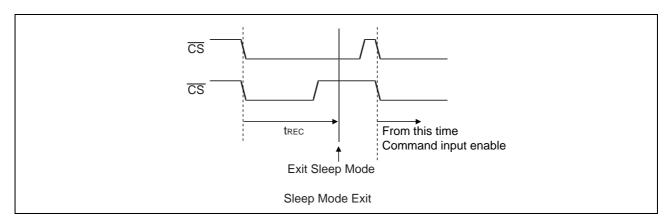
• SLEEP

The SLEEP command shifts the LSI to a low power mode called "SLEEP mode". The transition to the SLEEP mode is carried out at the rising edge of CS after operation code in the SLEEP command. However, when at least one SCK clock is inputted before the rising edge of CS after operation code in the SLEEP command, this SLEEP command is canceled.

After the SLEEP mode transition, SCK and SI inputs are logically ignored and SO changes to a High-Z state. When inputs other than $\overline{\text{CS}}$ are not fixed to VCC or VDD, in some case a shoot-through current may flow.



Returning to an normal operation from the SLEEP mode is carried out after t_{REC} (Max 400 μ s) time from the falling edge of \overline{CS} (see the <u>fig</u>ure below). It is possible to return \overline{CS} to H level before t_{REC} time. However, it is prohibited to bring down \overline{CS} to L level again during t_{REC} period.



■ BLOCK PROTECT

Writing protect block for WRITE command is configured by the value of BP0 and BP1 in the status register.

BP1	BP0	Protected Block
0	0	None
0	1	1800н to 1FFFн (upper 1/4)
1	0	1000н to 1FFFн (upper 1/2)
1	1	0000н to 1FFFн (all)

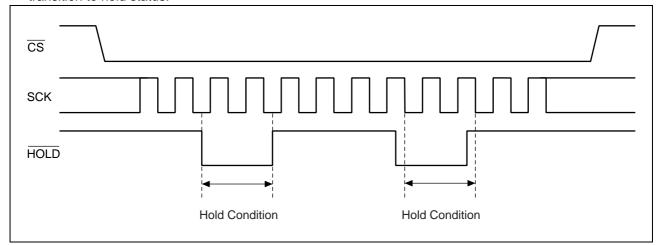
■ WRITING PROTECT

Writing operation of the WRITE command and the WRSR command are protected with the value of WEL, WPEN, WP as shown in the table.

WEL	WPEN	WP	Protected Blocks	Unprotected Blocks	Status Register
0	Х	Х	Protected	Protected	Protected
1	0	Х	Protected	Unprotected	Unprotected
1	1	0	Protected	Unprotected	Protected
1	1	1	Protected	Unprotected	Unprotected

■ HOLD OPERATION

Hold status is retained without aborting a command if HOLD is "L" level while CS is "L" level. The timing for starting and ending hold status depends on the SCK to be "H" level or "L" level when a HOLD pin input is transited to the hold condition as shown in the diagram below. In case the HOLD pin transited to "L" level when SCK is "L" level, return the HOLD pin to "H" level at SCK being "L" level. In the same manner, in case the HOLD pin transited to "L" level when SCK is "H" level, return the HOLD pin to "H" level at SCK being "H" level. Arbitrary command operation is interrupted in hold status, SCK and SI inputs become do not care. And, SO becomes High-Z while reading command (RDSR, READ). If CS is rising during hold status, a command is aborted. In case the command is aborted before its recognition, WEL holds the value before transition to hold status.



■ ABSOLUTE MAXIMUM RATINGS

Parameter	Symbol	Ra	Unit	
Parameter	Symbol	Min	Max	Onit
Power supply voltage*	V _{DD}	- 0.5	+ 6.0	V
Input voltage*	Vin	- 0.5	$V_{DD} + 0.5 (\le 6.0)$	V
Output voltage*	Vouт	- 0.5	$V_{DD} + 0.5 (\le 6.0)$	V
Operation ambient temperature	TA	- 40	+ 125	°C
Storage temperature	Tstg	- 55	+ 150	°C

^{*:} These parameters are based on the condition that Vss is 0 V.

WARNING: Semiconductor devices may be permanently damaged by application of stress (including, without limitation, voltage, current or temperature) in excess of absolute maximum ratings.

Do not exceed any of these ratings.

■ RECOMMENDED OPERATING CONDITIONS

Parameter	Symbol		Unit			
r arameter	Symbol	Min	Тур	Max	Offic	
Power supply voltage*1	V_{DD}	2.7	_	5.5	V	
Operation ambient temperature*2	TA	- 40	_	+ 125	°C	

^{*1:} These parameters are based on the condition that Vss is 0 V.

WARNING: The recommended operating conditions are required in order to ensure the normal operation of the semiconductor device. All of the device's electrical characteristics are warranted when the device is operated under these conditions.

Any use of semiconductor devices will be under their recommended operating condition. Operation under any conditions other than these conditions may adversely affect reliability of device and could result in device failure.

No warranty is made with respect to any use, operating conditions or combinations not represented on this data sheet. If you are considering application under any conditions other than listed herein, please contact sales representatives beforehand.

^{*2:} Ambient temperature when only this device is working. Please consider it to be the almost same as the package surface temperature.

■ ELECTRICAL CHARACTERISTICS

1. DC Characteristics

(within recommended operating conditions)

Parameter	Symbol	mbol Condition			Value		Unit	
Parameter	Symbol			Min	Min Typ Ma			
Input leakage current*1		$\overline{\text{WP}}$, $\overline{\text{HOLD}}$, SCK, $\overline{\text{CS}}$	25 °C			1	μΑ	
Imput leakage current	liril	$SI = 0 V to V_{DD}$	125 °C		_	2	μΛ	
Output leakage current*2	ILO	$SO = 0 \text{ V to V}_{DD}$	25 °C		_	1	μΑ	
Output leakage current	lirol	30 = 0 V to Vbb	125 °C		_	2	μΛ	
Operating power supply	IDD	SCK = 33MHz			1.9	2.3	mA	
current*3	IDD	SCK = 25MHz	_	1.5	1.8			
Standby current	İsb	SCK = SI = CS = WP = HOLD = V	_	13	30	μА		
Sleep current	Izz	CS = V _{DD} All other inputs V _{SS} or V _{DD}		_	5	12	μА	
Input high voltage	Vıн	V _{DD} = 2.7 V to 5.5 V		$V_{\text{DD}} \times 0.7$	_	V _{DD} + 0.3	V	
Input low voltage	VIL	V _{DD} = 2.7 V to 5.5	- 0.3	_	$V_{\text{DD}} \times 0.3$	V		
Output high voltage	Vон	lон = −2 mA	V _{DD} - 0.5	—	_	V		
Output low voltage	Vol	IoL = 2 mA		_	—	0.4	V	

^{*1 :} Applicable pin : $\overline{\text{CS}}$, $\overline{\text{WP}}$, $\overline{\text{HOLD}}$, SCK, SI

^{*2 :} Applicable pin : SO

 $^{^*3}$: Input voltage magnitude : VDD - 0.2 V or VSS

2. AC Characteristics

Parameter	Symbol		lue V to 4.5 V)	Va (V _{DD} = 4.5)	Unit	
		Min	Max	Min	Max	
SCK clock frequency	fск	0	25	0	33	MHz
Clock high time	tсн	15	_	13	_	ns
Clock low time	tcL	15	_	13	_	ns
Chip select set up time	t csu	10	_	10	_	ns
Chip select hold time	t csH	10		10		ns
Output disable time	top		16	_	16	ns
Output data valid time	todv		18	_	13	ns
Output hold time	tон	0	_	0	_	ns
Deselect time	t□	40	_	40	_	ns
Data in rising time	t R		50	_	50	ns
Data falling time	t⊧		50	_	50	ns
Data set up time	t su	5	_	5	_	ns
Data hold time	tн	5	_	5	_	ns
HOLD set uptime	t HS	10	_	10	_	ns
HOLD hold time	tнн	10		10	_	ns
HOLD output floating time	t HZ	_	20	_	20	ns
HOLD output active time	t LZ	_	20	_	20	ns
SLEEP recovery time	t rec		400		400	μS

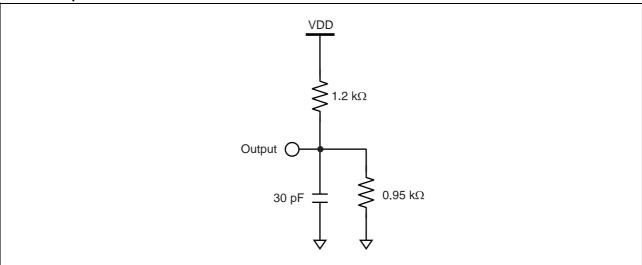
AC Test Condition

Power supply voltage : 2.7 V to 5.5 V Operation Operation ambient temperature : - 40 °C to + 125 °C $Input \ voltage \ magnitude \qquad \qquad : \ V_{\text{DD}} \times 0.7 \leq V_{\text{IH}} \leq V_{\text{DD}}$

 $0 \leq V_{\text{IL}} \leq V_{\text{DD}} \times 0.3$

: 5 ns Input rising time Input rising time
Input falling time
Input judge level : 5 ns Input judge level : V_{DD}/2 Output judge level : V_{DD}/2

AC Load Equivalent Circuit



3. Pin Capacitance

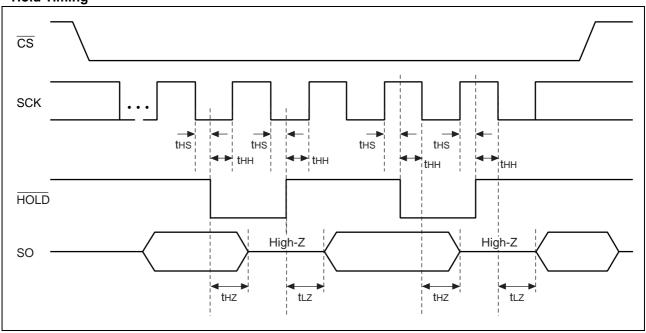
Parameter	Symbol	Condition	Va	Unit	
Farameter	Syllibol	Condition	Min	Max	
Output capacitance	Со	$V_{DD} = 5.0 \text{ V},$ $V_{IN} = V_{OUT} = 0 \text{ V to } V_{DD},$	_	8	pF
Input capacitance	Сι	f = 1 MHz, T _A = +25 °C		6	pF

■ TIMING DIAGRAM

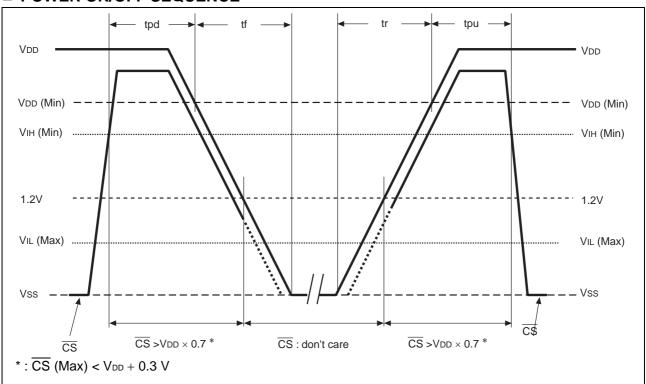
• Serial Data Timing CS ► tcsH tcsu tcH tCL tcH SCK tsu Valid in SI todv tон top High-Z High-Z SO

• Hold Timing

: H or L



■ POWER ON/OFF SEQUENCE



Parameter	Symbol	Val	Unit	
Farameter	Symbol	Min	Max	Offic
CS level hold time at power OFF	tpd	400	_	ns
CS level hold time at power ON	tpu	250	_	μS
Power supply rising time	tr	0.05		ms/V
Power supply falling time	tf	0.1		ms/V

If the device does not operate within the specified conditions of read cycle, write cycle or power on/off sequence, memory data can not be guaranteed.

■ FRAM CHARACTERISTICS

Parameter	Value		Unit	Remarks	
raiametei	Min	Max	Onit	iveillai ks	
Read/Write Endurance*1	10 ¹³		Times/byte	Operation Ambient Temperature T _A = + 125 °C	
	3.3 or more*3			Operation Ambient Temperature T _A = + 125 °C	
Data Retention*2	10.9		Years	Operation Ambient Temperature T _A = + 105 °C	
	40.2			Operation Ambient Temperature T _A = +85 °C	

^{*1:} Total number of reading and writing defines the minimum value of endurance, as an FRAM memory operates with destructive readout mechanism.

■ NOTE ON USE

We recommend programming of the device after reflow. Data written before reflow cannot be guaranteed.

^{*2:} Minimum values define retention time of the first reading/writing data right after shipment, and these values are calculated by qualification results.

^{*3:} Under evaluation for more than 3.3 year(+125 $^{\circ}$ C).

■ ESD AND LATCH-UP

Test	DUT	Value
ESD HBM (Human Body Model) JESD22-A114 compliant		≥ 2000 V
ESD MM (Machine Model) JESD22-A115 compliant	MESSESSANASANS	≥ 200 V
ESD CDM (Charged Device Model) JESD22-C101 compliant	MB85RS64VYPNF-GS-BCE1 MB85RS64VYPNF-GS-BCERE1	≥ 1000 V
Latch-Up (I-test) JESD78 compliant		≥ 125 mA
Latch-Up (V _{supply} overvoltage test) JESD78 compliant		≥ 8.25V

■ REFLOW CONDITIONS AND FLOOR LIFE

[JEDEC MSL] : Moisture Sensitivity Level 3 (ISP/JEDEC J-STD-020D)

■ Current status on Contained Restricted Substances

This product complies with the regulations of REACH Regulations, EU RoHS Directive and China RoHS.

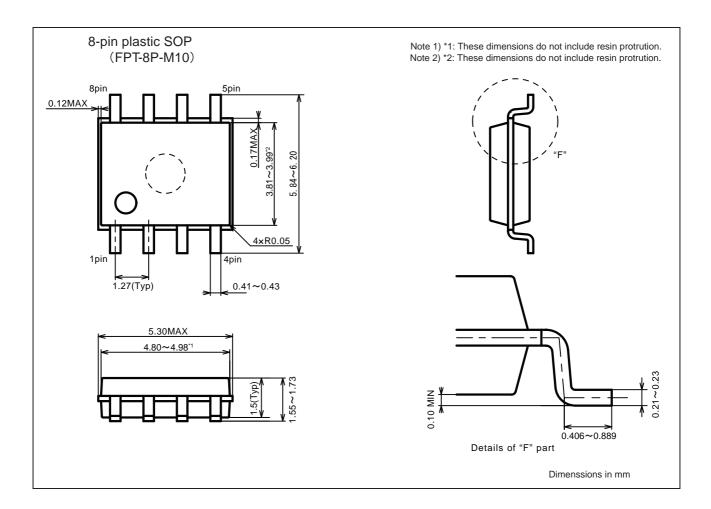
■ ORDERING INFORMATION

Part number	Package	Shipping form	Minimum shipping quantity
MB85RS64VYPNF-GS-BCE1	8-pin plastic SOP (FPT-8P-M10)	Tube	*
MB85RS64VYPNF-GS-BCERE1	8-pin plastic SOP (FPT-8P-M10)	Embossed Carrier tape	1500

^{*:} Please contact our sales office about minimum shipping quantity.

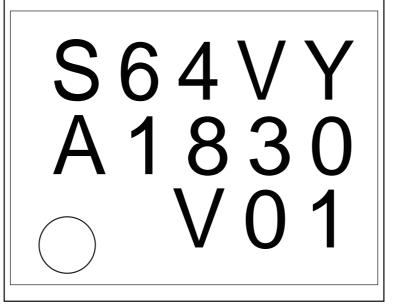
■ PACKAGE DIMENSION

8-pin plastic SOP	Lead pitch	1.27 mm
	Package width × package length	3.9 mm×4.89 mm
	Lead shape	Gullwing
	Sealing method	Plastic mold
	Mounting heigth	1.73 mm MAX
(FPT-8P-M10)		



■ MARKING (Example)

[MB85RS64VYPNF-GS-BCE1] [MB85RS64VYPNF-GS-BCERE1]



[FPT-8P-M10]

S64VY: Product Name

A1830: A(CS code) + 1830 (Year and Week code)

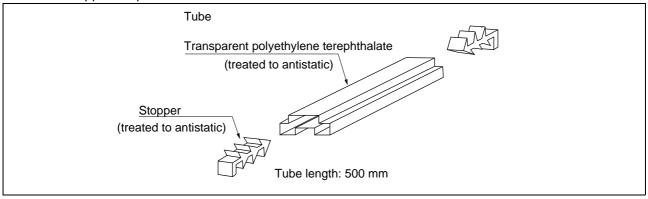
V01: V(Factory code) + 01(Trace code)

■ PACKING INFORMATION

1. Tube

1.1 Tube Dimensions

• Tube/stopper shape



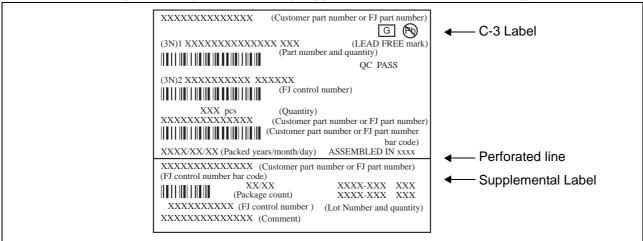
• Tube cross-sections and Maximum quantity

		N	1aximum qua	antity
Package form	Package code	pcs/ tube	pcs/inner box	pcs/outer box
SOP, 8, plastic (2)	FPT-8P-M10	85	4250	17000
9.5 4.5 3.9				
Transparent polyethylene terephthalate				

(Dimensions in mm)

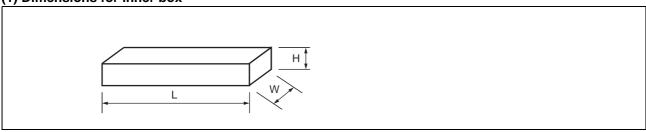
1.2 Product label indicators

Label I: Label on Inner box/Moisture Barrier Bag/ (It sticks it on the reel for the emboss taping) [C-3 Label (50mm × 100mm) Supplemental Label (20mm × 100mm)]



1.3 Dimensions for Containers

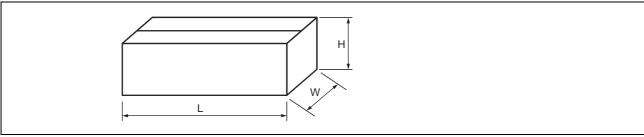
(1) Dimensions for inner box



L	W	Н
540	125	75

(Dimensions in mm)

(2) Dimensions for outer box



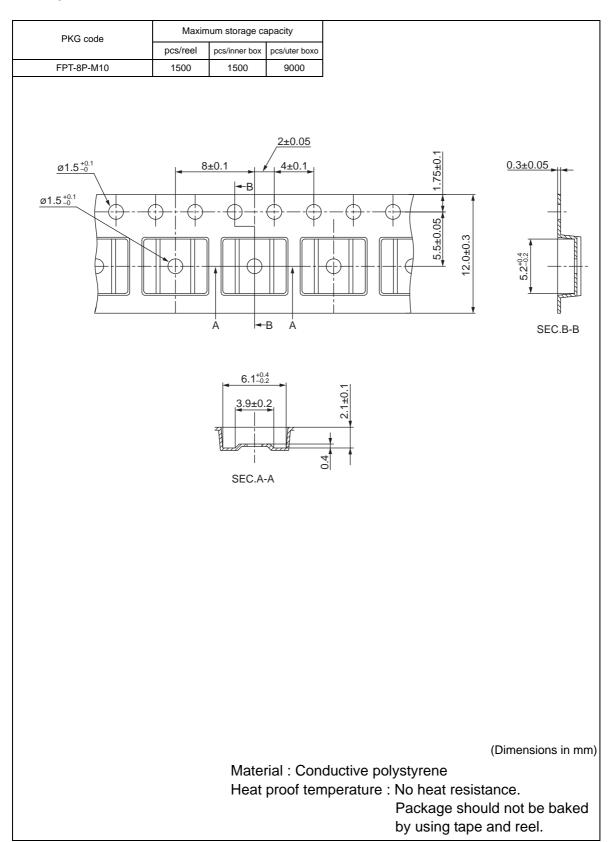
L	W	Н
549	277	180

(Dimensions in mm)

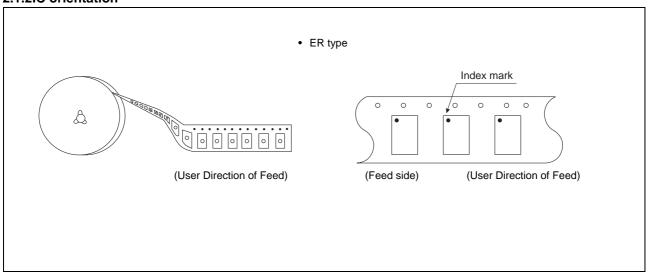
2. Emboss Tape

2.1 FPT-8P-M10

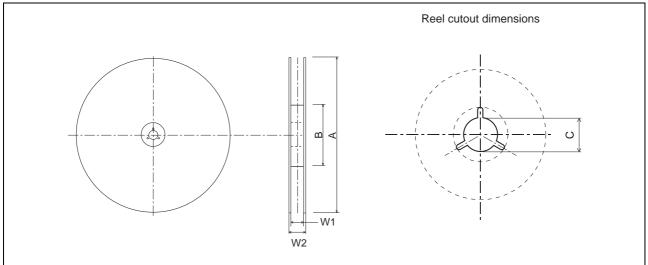
2.1.1Tape Dimensions



2.1.2IC orientation



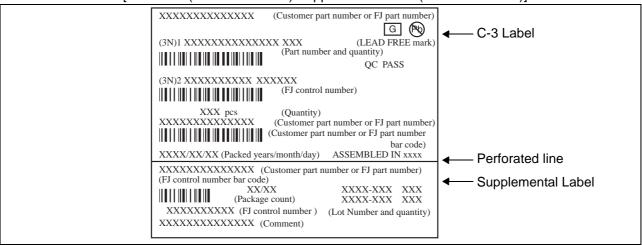
2.1.3Reel dimensions



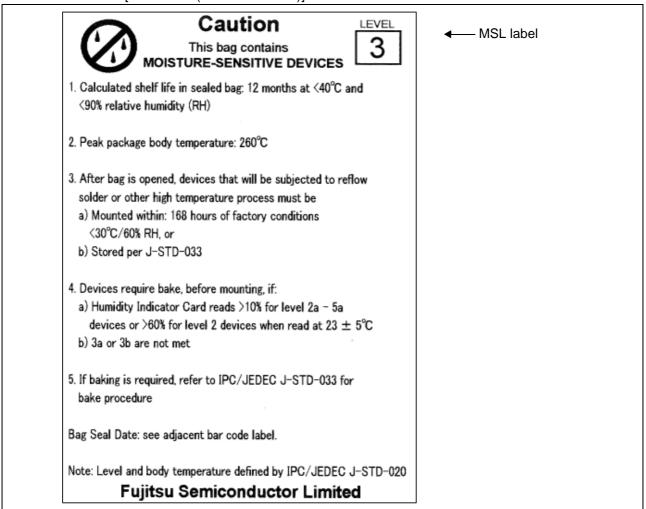
Dimensions in mm

Tape width	Α	В	С	W1	W2
12	254±2	100±1	13±0.2	13.5±1.0	17.5±1.0

Label I: Label on Inner box/Moisture Barrier Bag/ (It sticks it on the reel for the emboss taping) [C-3 Label (50mm × 100mm) Supplemental Label (20mm × 100mm)]



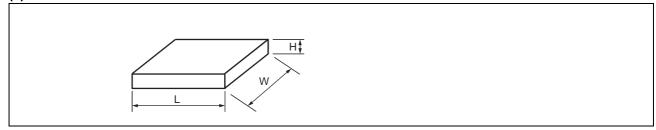
Label II: Moisture Barrier Bag *(It sticks it on the Aluminum laminated bag) [MSL Label (100mm × 70mm)]



*: MLS label is attached only to following part number. MB85RS64VYPNF-GS-BCERE1

2.3 Dimensions for Containers

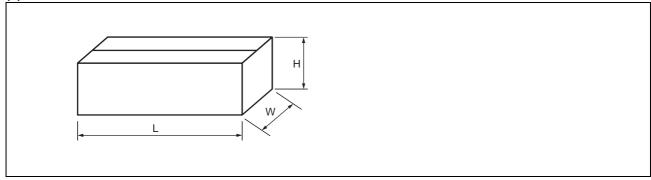
(1) Dimensions for inner box



Tape width	L	W	Н
12	265	262	51

(Dimensions in mm)

(2) Dimensions for outer box



L	W	Н
549	277	180

(Dimensions in mm)

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